Issue Classification	Application/Control No.	Applicant(s)/Patent Under Reexamination FALSAFI ET AL.
	Examiner	Art Unit
	Yoon, Tae H	1714

	ORIGINAL	AL	INTERNA	INTERNATIONAL CLASSIFICATION	
	CLASS	SUBCLASS	CLAIMED	NON-CLAIMED	AIMED
523	1	115	A 6 1 K	6/083	
	CROSS REFERENCE/S)	SENCE(S)	C 0 8 K	5/41	
		(2)	A 6 1 C	2 / 00	
CLASS	SUBCLASS (ON	SUBCLASS (ONE SUBCLASS PER BLOCK)			
523	118				
524	167				
433	228.1				
		•			
		•			
NONE				Total Claims Allowed:	: Allowed:
(Assistant Examiner)	iner) (Date)				
		Tae H Yoon Colon	02/08/2007	O.G. Print Claim(s)	O.G. Print Figure
(Legal-Instruments Examiner)	nts Examiner) (Date)	(Primary Examiner)	(Date)	-	

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